

Search Notes

Application/Control No.

10/649,625

Examiner

Jim Vannucci

Applicant(s)/Patent under
Reexamination

SEKI, YUICHI

Art Unit

2828

SEARCHED

Class	Subclass	Date	Examiner

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
wafer lot, laser chips	11/8/2005	JV